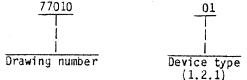
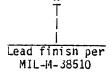
		REVISIONS		
	LTR	DESCRIPTION	DATE	APPROVED
-	D	Change R _L to 2 kΩ. Convert to military drawing format Remove vendor, CAGE 27014.	16 Oct 1986	Milkands
	E	Add footnote to table I. Change max frequency. Add LCC package. Add vendor CAGE 04713. Editorial changes throughout. Change logic diagram.	21 OCT. 1987	RPEvans

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- 1.1 Scope. This drawing describes device requirements for class B microcircuits in accordance with 1.2.1 of MIL-STD-883, "Provisions for the use of MIL-STD-883 in conjunction with compliant non-JAN devices".
 - 1.2 Part number. The complete part number small be as shown in the following example:







1.2.1 Device type. The device type shall identify the circuit function as follows:

Device type

Generic number

Circuit

01

54LS196

30 MHz presettable decade or binary counter

1.2.2 <u>Case outlines</u>. The case outlines shall be as designated in appendix C of MIL-M-38510, and as follows:

package

Outline letter

Case outline

C D 2 D-1 (14-lead, 1/4" x 3/4"), dual-in-line package F-2 (14-lead, 1/4" x 3/8"), flat-package C-2 (20-terminal, .350" x .350"), square chip carrier

1.3 Absolute maximum ratings.

-0.5 V dc to +7.0 V dc -1.5 V dc at -18 mA to 5.5 V dc -65°C to +150°C 149 mW +300°C (See_MIL-M-38510, appendix C)

1.4 Recommended operating conditions.

Supply voltage (V_{CC}) - - - - - - - - - - - Minimum high level input voltage (V_{IH}) - - - - Maximum low level input voltage (V_{IL}) - - - - - Case operating temperature range (T_C) - - - - -

4.5 V dc minimum to 5.5 V dc maximum 2.0 V dc

0.7 V dc -55°C to +125°C

+175°C

1/ Must withstand the added P_{D} due to short-circuit test (e.g., I_{OS}).

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2. APPLICABLE DOCUMENTS

2.1 Government specification and standard. Unless otherwise specified, the following specification and standard, of the issue listed in that issue of the Department of Defense Index of Specifications and Standards specified in the solicitation, form a part of this drawing to the extent specified herein.

SPECIFICATION.

MILITARY

MIL-M-38510

Microcircuits, General Specification for.

STANDARD

MILITARY

MIL-STD-883

Test Methods and Procedures for Microelectronics.

(Copies of the specification and standard required by manufacturers in connection with specific acquisition functions should be obtained from the contracting activity or as directed by the contracting activity.)

REQUIREMENTS

- 3.1 Item requirements. The individual item requirements shall be in accordance with 1.2.1 of MIL-STD-883, "Provisions for the use of MIL-STD-883 in conjunction with compliant non-JAN devices" and as specified herein.
- 3.2 Design, construction, and physical dimensions. The design, construction, and physical dimensions shall be as specified in MIL-M-38510 and herein.
 - 3.2.1 Terminal connections. The terminal connections shall be as specified on figure 1.
 - 3.2.2 Logic diagram. The logic diagram shall be as specified on figure 2.
 - 3.2.3 Truth table. The truth table shall be as specified on figure 3.
 - 3.2.4 Case outlines. The case outlines shall be in accordance with 1.2.2 herein.
- 3.3 Electrical performance characteristics. Unless otherwise specified, the electrical performance characteristics are as specified in table I and apply over the full recommended case operating temperature range.
- 3.4 Marking. Marking shall be in accordance with MIL-STD-883 (see 3.1 herein). The part shall be marked with the part number listed in 1.2 herein. In addition, the manufacturer's part number may also be marked as listed in 6.4 herein.
- 3.5 <u>Certificate of compliance</u>. A certificate of compliance shall be required from a manufacturer in order to be listed as an approved source of supply in 5.4. The certificate of compliance submitted to DESC-ECS prior to listing as an approved source of supply shall state that the manufacturer's product meets the requirements of MIL-STD-883 (see 3.1 herein) and the requirements herein.

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		TABLE I. Ele				cter	istics.				
Test	Symbol	-5 unl	Condition $5^{\circ}C \leq T_{C} \leq 10^{\circ}$	itions < +125° √ise sp	С,		Group subgrou		Min	nts Max	 Unit
High level output voltage	V _{OH}	V _{CC} = 4.5 V I _{OH} = -400	; V _{IN} = 0. _m A	.7 V or	2.0 V		1,2,3		2.5		V
Low level output voltage	V _{OL}	V _{CC} = 4.5 V I _{OL} = 4 mA	V; V _{IN} = 0.7 V or 2.0 V							0.4	Y
Input clamp voltage	AIC	V _{CC} = 4.5 V T _C = +25°C	; I _{IN} = -18 mA;			1	* · · · · · · · · · · · · · · · · · · ·		-1,5	\ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \	
High level input current	IIHI	V _{CC} = 5.5 Y V _{IH} = 2.7 Y	Data, Co	ount/Lo	ad		1,2,3			20	μA
·	I _{IH2}	V _{CC} = 5.5 V V _{IH} = 2.7 V	Clear, C Clock 2	lock 1			1,2,3			40 80	μ Α μ Α
	I IH3	V _{CC} = 5.5 V V _{IH} = 5.5 V	Data, Co	unt/Lo	ıd		1,2,3			100	μА
	 I	V _{CC} = 5.5 V V _{IH} = 5.5 V	Clear, C Clock 2	lock 1			1,2,3			200	μA μA
ow level input current	IIIL1	V _{CC} = 5.5 V V _{IL} = 0.4 V	Data, Co	unt/Lo	ıd	,	1,2,3			 -400 	μA
	I IL2	V _{CC} = 5.5 Y V _{IL} = 0.4 Y	Clear				1,2,3			 -800 	μA
	I IL3	V _{CC} = 5.5 V V _{IL} = 0.4 V	Clock 1				1,2,3			-2.4	l mA
	I _{IL4}	V _{CC} = 5.5 V V _{IL} = 0.4 V	Clock 2				1,2,3	,		-2.8	mA
hort-circuit output current	Ios	V _{CC} = 5.5 V	1/				1,2,3		 -6 	-130 	mA
upply current	Icc	V _{CC} = 5.5 V					1,2,3			27 	l mA
unctional tests		See 4.3.1c					7				
ee footnotes at en	d of tabl	е.									
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	T	Conditions		Lim	íts	<u> </u>
Test	Symbol	Conditions -55°C < T _C < +125°C, unless otherwise specified	Group A subgroups	Min	Max	T Unit
laximum clock frequency	IF _{MAX}	V _{CC} = 5.0 V R _L = 2 kΩ ±5%	9	25		MHZ
Clock 1	 	CL = 50 pF ±10% 2/	10, 11	17		 MHz
Propagation delay	t _{PLH1}	-	9		20	l ns
ገock 1 to QA			10, 11		28	ns
	t _{PHL1}		9		30	ns
			10, 11		35	ns
time	 t _{PLH2} 		9		29	ns
Clock 2 to QB			10, 11		41	ns
	tpHL2		9		42	ns
	 -		10, 11		53	ns
time	i tpLH3 		9		68	ns
∏ock 2 to QC			10, 11		87	ns
	l tpHL3 		9		72	ns
			10, 11		94	ns
time, low-to-high	l tpLH4 ·		9		23	ns
level lock 2 to QD			10, 11	1	32	ns

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	Ţ	T	Lim	its	 	
Test	Symbol	Conditions -55°C < T _C < +125°C, unless otherwise specified	Group A subgroups	Min	Max	⊤ Unit
Propagation delay time, high-to-low level	tpHL4	V _{CC} = 5.0 V	9		54	ns
Clock 2 to QD		= 30 pr 210% 2/	10, 11		70	ns
Propagation delay	t _{PLH5}		9		35	ns
A,B,C,D to QA,QB,	1	10, 11		 49 	ns	
	tPHL5		9		 53 	ns
			10, 11		 69 	ns
Propagation delay	l tpLH6 		9		45	ns
oad to any output		1	10, 11		64	ns
	t _{PHL6}		9] 	54	ns
		1	10, 11		70	l ns
ropagation delay time, high-to-low level	t _{PHL7}		9		60	l ns
lear to any			10, 11	: l	78	ns

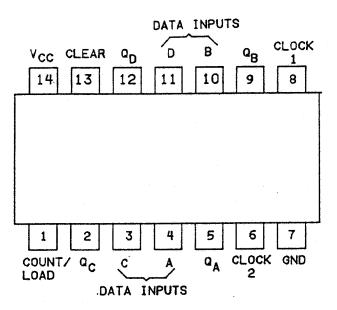
^{1/} Not more than one output should be shorted at a time, and the duration of the short-circuit condition should not exceed 1 second.

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output

^{2/} Propagation delay time testing may be performed using either $C_L = 15$ pF or $C_L = 50$ pF. However, the manufacturer must certify and guarantee that the microcircuits meet the switching test limits specified for a 50-pF load.

Cases C and D



Case 2

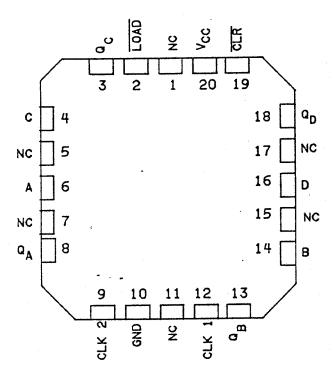


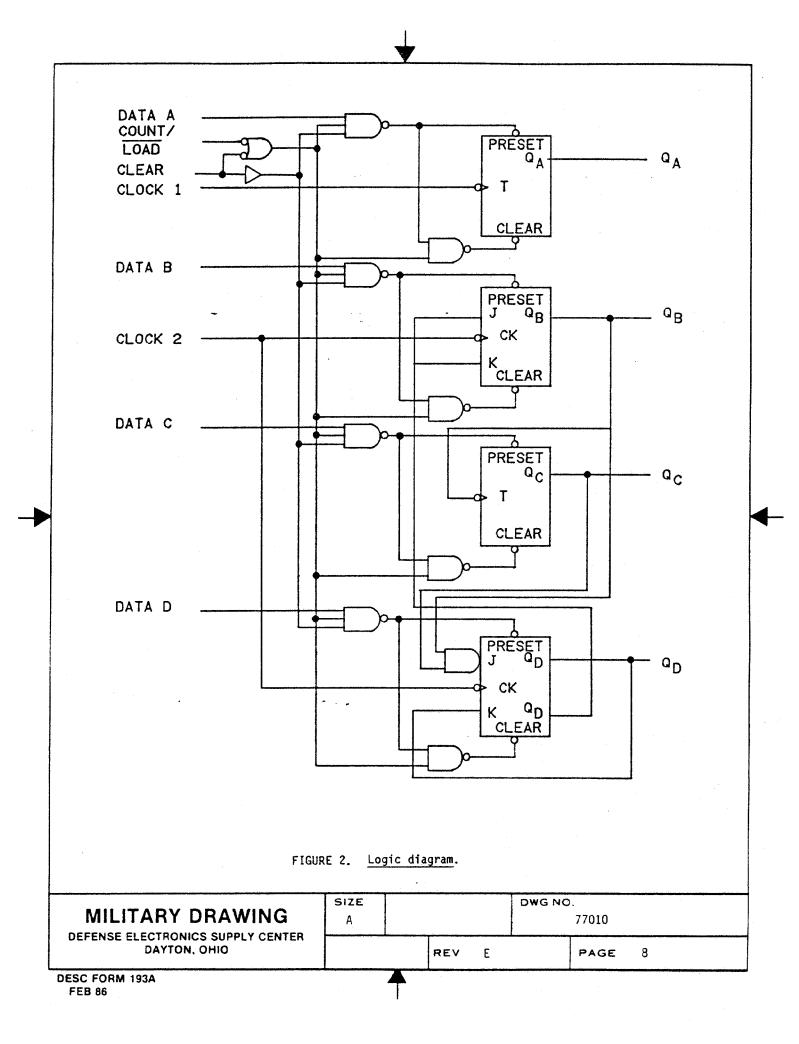
FIGURE 1. Terminal connections.

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		Outp	out	
 Count	QD	QC	QB	QA
0 1 2 3 4 5 6 7 8 8 9	L L L L H H	L L L H H H H L L		L H L H L H L H

H = High level, L = Low level

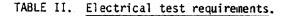
NOTE: Output \mathbb{Q}_A connected to Clock 2 input.

FIGURE 3. Truth table.

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- 3.6 Certificate of conformance. A certificate of conformance as required in MIL-STD-883 (see 3.1 herein) shall be provided with each lot of microcircuits delivered to this drawing.
- 3.7 Notification of change. Notification of change to DESC-ECS shall be required in accordance with MIL-STD-883 (see 3.1 herein).
- 3.8 <u>Verification and review.</u> DESC, DESC's agent, and the acquiring activity retain the option to review the manufacturer's facility and applicable required documentation. Offshore documentation shall be made available onshore at the option of the reviewer.
 - 4. QUALITY ASSURANCE PROVISIONS
- 4.1 Sampling and inspection. Sampling and inspection procedures shall be in accordance with section 4 of MIL-M-38510 to the extent specified in MIL-STD-883 (see 3.1 herein).
- 4.2 <u>Screening.</u> Screening shall be in accordance with method 5004 of MIL-STD-883, and shall be conducted on all devices prior to quality conformance inspection. The following additional criteria shall apply:
 - a. Burn-in test (method 1015 of MIL-STD-883).
 - (1) Test condition A, B, C, or D using the circuit submitted with the certificate of compliance (see 3.5 herein).
 - (2) $T_A = +125^{\circ}C$, minimum.
 - b. Interim and final electrical test parameters shall be as specified in table II herein, except interim electrical parameter tests prior to burn-in are optional at the discretion of the manufacturer.
- 4.3 Quality conformance inspection. Quality conformance inspection shall be in accordance with method $\overline{5005}$ of MIL-STD-883 including groups A, B, C, and D inspections. The following additional criteria shall apply.
 - 4.3.1 Group A inspection.
 - a. Tests shall be as specified in table II herein.
 - b. Subgroups 4, 5, 6, and 8 in table I, method 5005 of MIL-STD-883 shall be omitted.
 - c. Subgroup 7 tests shall verify the truth table.
 - 4.3.2 Groups C and D inspections.
 - a. End-point electrical parameters shall be as specified in table II herein.
 - b. Steady-state life test (method 1005 of MIL-STD-883) conditions:
 - (1) Test condition A, B, C, or D using the circuit submitted with the certificate of compliance (see 3.5 herein).
 - (2) $T_A = +125^{\circ}C$, minimum.
 - (3) Test duration: 1,000 hours, except as permitted by appendix B of MIL-M-38510 and method 1005 of MIL-STD-883.

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MIL-STD-883 test requirements	Subgroups (per method 5005, table I)
 Interim electrical parameters (method 5004)	
Final electrical test parameters (method 5004)	1*, 2, 3, 9
Group A test requirements (method 5005)	1, 2, 3, 7, 9, 10, 11**
Groups C and D end-point electrical parameters (method 5005)	1, 2, 3

* PDA applies to subgroup 1.

5. PACKAGING

5.1 Packaging requirements. The requirements for packaging shall be in accordance with MIL-M-38510.

6. NOTES

- 6.1 Intended use. Microcircuits conforming to this drawing are intended for use when military specifications do not exist and qualified military devices that will perform the required function are not available for OEM application. When a military specification exists and the product covered by this drawing has been qualified for listing on QPL-38510, the device specified herein will be inactivated and will not be used for new design. The QPL-38510 product shall be the preferred item for all applications.
 - 6.2 Replaceability. Replaceability is determined as follows:
 - a. Microcircuits covered by this drawing will replace the same generic device covered by a contractor-prepared specification or drawing.
 - b. When a QPL source is established, the part numbered device specified in this drawing will be replaced by the microcircuit identified as part number M38510/32001B--.
- 6.3 Comments. Comments on this drawing should be directed to DESC-ECS, Dayton, Ohio 45444, or telephone 513-296-5375.

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^{**} Subgroups 10 and 11, if not tested, shall be guaranteed to the specified limits in table I.

6.4 Approved sources of supply. Approved sources of supply are listed herein. Additional sources will be added as they become available. The vendors listed herein have agreed to this drawing and a certificate of compliance (see 3.5) has been submitted to DESC-ECS.

Military drawing part number	 Vendor CAGE number	Vendor similar part number 1/	Replacement
7701001CX 2/	01295 04713	 SNJ54LS196J 54LS196/BCAJC 	M38510/32001BCX
7701001DX	01295	 SNJ54LS196W 	M38510/32001BDX
 77010012X - 	01295 04713	 SNJ54LS196FK 54LS196M/B2AJC 	

 $[\]frac{1}{\text{Caution.}}$ Do not use this number for item acquisition. Items acquired to this number may not satisfy the performance requirements of this drawing.

2/ Inactive for new design as of October 1984. Use QPL-38510 product.

Vendor CAGE number	Yendor name and address					
01295	Texas Instruments, Incorporated P.O. Box 6448 Midland, TX 79701					
04713	Motorola, Incorporated 7402 South Price Road Tempe, AZ 85283					

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